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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): ANATOLY FABRIKANT, GUOHENG ZHAO, DANIEL C. WACK
and MEHRDAD NIKOONAHAD
Assignee: KLA-TENCOR TECHNOLOGIES CORPORATION
Title: IMPROVED SYSTEM FOR SCATTEROMETRIC
MEASUREMENTS AND APPLICATIONS
Serial No.: 09/671,715 Filing Date: September 27, 2000
Examiner: Unknown Group Art Unit: 2877
Docket No.: M-10699 US

San Jose, California
April 24, 2001

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants wish to call the enclosed documents to the attention of the Examiner. A PTO form 1449 listing these documents is enclosed.

Citation of the above documents shall not be construed as:

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T. L. Kaplan 4/24/01

Tammy L. Kaplan Date of Signature

Respectfully submitted,

James S. Hsue
James S. Hsue
Attorney for Applicant(s)
Reg. No. 29,545

LAW OFFICES OF
SKJERVEN MORRILL
MacPHERSON LLP

25 METRO DRIVE
SUITE 700
SAN JOSE, CA 95110
(408) 453-9200
FAX (408) 453-7979

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U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.		Serial No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				M-10699 US		09/671,715	
(Use several sheets if necessary)				Applicant(s)			
				ANATOLY FABRIKANT ET AL.			
				Filing Date		Group	
				September 27, 2000		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL	WO99/45340	9/10/99	International			X	
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
AQ	"Multilayer modal method for diffraction gratings of arbitrary profile, depth, and permittivity," L. Li, <i>J. Opt. Soc. Am. A.</i> , Vol. 10, No. 12, December 1993, pp. 2581-2591	
AR	"Rigorous coupled-wave analysis of planar-grating diffraction," M.G. Moharam et al., <i>J. Opt. Soc. Am.</i> , Vol. 71, No. 7, July 1981, pp. 811-818	
AS	"Coupled-Wave Analysis of Two-Dimensional Dielectric Gratings," M.G. Moharam, <i>SPIE, Vol. 883, Holographic Optics: Design and Applications</i> , 1988, pp. 8-11	

Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.